

IFW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE



August 19, 2005

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

## INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56 and in accordance with the practice under 37 C.F.R. §§ 1.97 and 1.98, the Examiner's attention is directed to the documents listed on the enclosed Form PTO-1449. Copies of the listed documents, other than U.S. patent documents, are enclosed.

JP 2001-94107 was cited in an international search report from which the subject application claims benefit of priority. A copy of the international search report is enclosed.

The following documents are discussed at the following pages of the specification:

<u>Documents</u>	<u>Page(s)</u>
U.S. Patent No. 5,596,208	3
U.S. Patent No. 5,625,199	3
U.S. Patent No. 5,574,291	3
Y.-Y. Lin, et al., IEEE Transactions on Electron Devices	4
JP 7-206599	4
JP 9-232589	5
Y.-Y. Lin, et al., IEEE Electron Device Letters	5
JP 2001-94107	6
R. B. Campbell, et al.	41

English-language abstracts for JP 2001-94107, JP 9-232589 and JP 7-206599 are also enclosed.

According to a commercial database, U.S. Patent No. 6,326,640 is in the same family as JP 9-232589, and U.S. Patent Nos. 5,556,706 and 5,546,889 are in the same family as JP 7-206599.

The Examiner's attention is also directed to the following U.S. Application:

<u>Application No.</u>	<u>Filing Date</u>	<u>Applicants</u>
10/532,078	04/21/2005	A. Unno N. Sato H. Miyazaki N. Doi

This Information Disclosure Statement is being filed before the issuance of a first Office Action on the merits. Therefore, no fee under 37 C.F.R. § 1.97(c)(2) is believed due. Nevertheless, the Commissioner may charge Deposit Account No. 06-1205, should any fee be due for filing this paper.

Applicant requests that the above information be considered by the Examiner and that a copy of the enclosed Form PTO-1449 be initialed and returned indicating that such information has been considered.

Applicant's undersigned attorney may be reached in our Costa Mesa, California office at (714) 540-8700. All correspondence should continue to be directed to our below-listed address.


Respectfully submitted,



Damond E. Vadnais  
Attorney for Applicant  
Registration No.: 52,310

FITZPATRICK, CELLA, HARPER & SCINTO  
30 Rockefeller Plaza  
New York, New York 10112-3800  
Facsimile: (212) 218-2200

FORM PTO 1449 (modified)  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			ATTY DOCKET NO. <b>03500.017331.</b>		APPLICATION NO. <b>10/517,529</b>	
			APPLICANT <b>AKIRA UNNO</b>			
			FILING DATE <b>June 19, 2003</b>		GROUP	



U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	6,783,588	8/31/04	Aoto, et al.	117	4		
	6,326,640	12/04/01	Shi, et al.	257	40		
	5,625,199	4/29/97	Baumbach, et al.	257	40		
	5,596,208	1/21/97	Dodabalapur, et al.	257	66		
	5,574,291	11/12/96	Dodabalapur, et al.	257	40		
	5,556,706	9/17/96	Wakita, et al.	428	421		
	5,546,889	8/20/96	Wakita, et al.	117	84		
	2004-0231581	11/25/04	Aoto, et al.	117	2		

FOREIGN PATENT DOCUMENTS							
DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT		
2001-94107	4/06/01	Japan			Abstract		
9-232589	5/09/97	Japan			Abstract		
7-206599	8/08/95	Japan			Abstract		

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)	
	Campbell, R. B, et al., "The Crystal and Molecular Structure of Pentacene", <i>Acta Cryst.</i> , Vol. 14, (1961) pp. 705-711.
	Lin, Y.-Y., et al. "Stacked Pentacene Layer Organic Thin-Film Transistors with Improved Characteristics", <i>IEEE Electron Device Letters</i> , Vol. 18, No. 12, (Dec. 1997) pp. 606-608.
	Lin, Y.-Y., "Pentacene-Based Organic Thin-film Transistors", <i>IEEE Transactions on Electron Devices</i> , Vol. 44, No. 8, (Aug. 1997) pp. 1325-1331.

EXAMINER	DATE CONSIDERED
----------	-----------------

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 1 of 1